

Search Notes

Application/Control No.

10/622,149

Examiner

Stephen W. Smoot

Applicant(s)/Patent under
Reexamination

ROBERDS ET AL.

Art Unit

2813

SEARCHED

Class	Subclass	Date	Examiner
438	455	3/4/2005	SWS
438	458	3/4/2005	SWS
438	459	3/4/2005	SWS
438	977	3/4/2005	SWS

S.W.S.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Considered all citations from parent application.	3/4/2005	S.W.S. SWS
Key Words: Wafer Thinning - Delamination; Implantation - Cleave, SMARTCUT, ELTRAN, Embrittlement;	3/4/2005	S.W.S. SWS
Polymer - Ether, Arylene, Ketone, Acetylene, Naphthylene, Polyarylene.	3/4/2005	S.W.S. SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	3/4/2005	S.W.S. SWS